

GENE-A55E

PCB Rev. A0.1_0_0

Temperature/Humidity Test Report

Report NO:

Summary	<p><input checked="" type="checkbox"/> Pass <input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p>
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Issue date

2014-07-04

Approval

Richard Wu

Test Engineer

Yungtang Lin

Test item list

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Testing Result

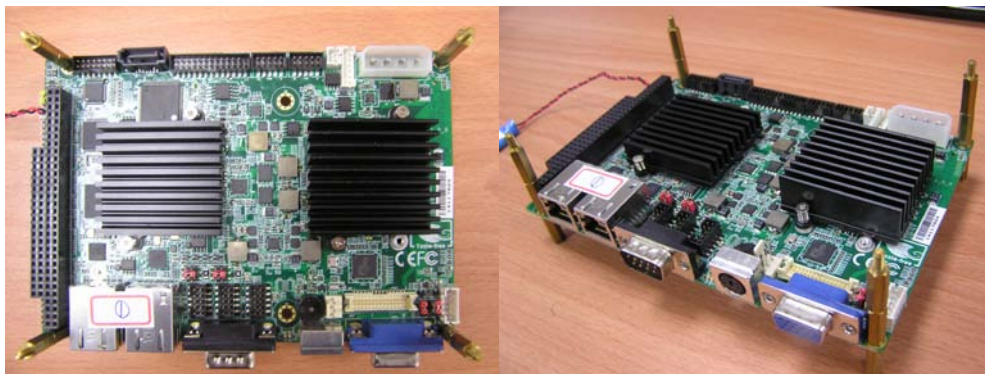
Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	N/A
2	Temperature variation operation test	Pass	N/A
3	Cold start and hot start test	Pass	N/A

Configuration of EUT

Test Product: GENE-A55E A0.1

Sample Configuration & Quantity Under Test:

1. **CPU:** AMD G-series T16R (615MHz Single Core)
2. **Chipset:** G-Series A55E Chipset
3. **VGA:** AMD Radeon HD 6320
4. **Memory:** Transecnd 4GB DDR3L 1066 SODIMM CL7
5. **BIOS Reversion:** GA5EAM02
6. **CFast:** N/A
7. **SATA HDD:** HITACHI 320GB MLC
8. **Test Software:** Windows 7 x64 with SP1/ Run PassMark BurnInTest Pro v7.0 build 1004
9. **Power Supply:** EMACS HG2-6400P (ATX-Mode)
10. **Cooler:**



Temp./humidity power on/off test

Test Date: 2014-07-03--07-04

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

Programmable Temperature & Humidity Chamber

TERCHY. TECH. CORP.

Model: MHU-150LB

Date of Calibration: 2014/03/17

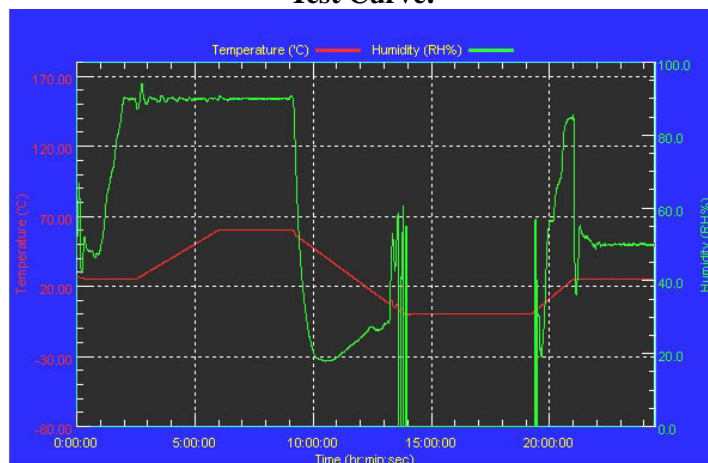
Serial Number: 961138

Temperature & Humidity Power On/Off Test:

Testing Specification:

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate
Power On/Off	1782/ times	1782/ times	0 %
Note: Failure rate need to 0%.			

Temperature variation operation test

Test Date: 2014-06-26~06-27

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

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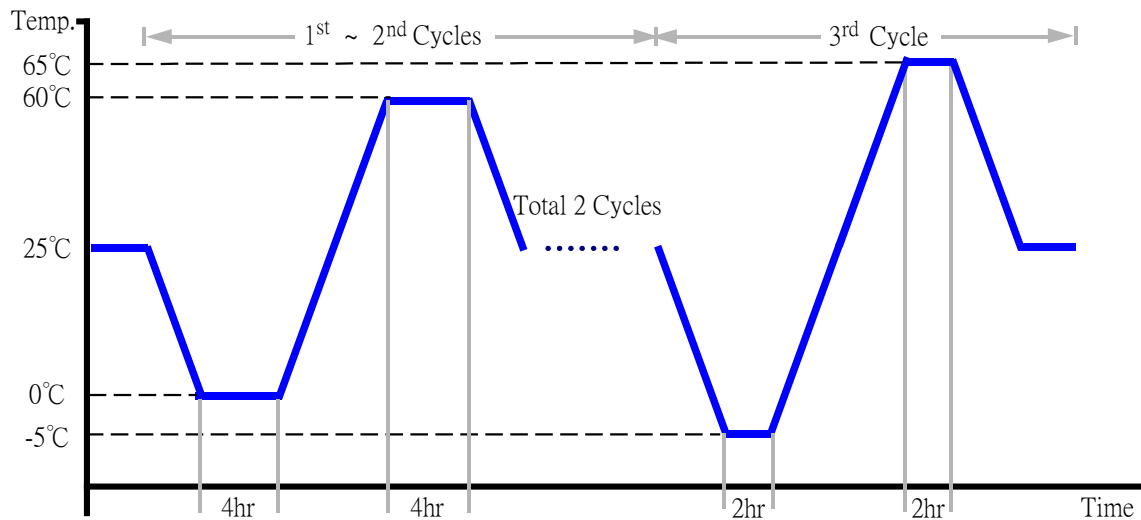
Model: MHU-150LB

Date of Calibration: 2014/03/17

Serial Number: 961138

Temperature & Humidity Cycle Test:

1. Test Low Temperature: **0°C** (1st~2nd cycles)
-5°C (3rd cycle)
2. Test High Temperature: **60°C** (1st~2nd cycles)
65°C (3rd cycle)
3. Test dwell time: **4Hrs** (1st~2nd cycles)
2Hrs (3rd cycle)
4. Temperature slope: **2°C/min**
5. Test cycle: **3 cycles**
6. Test Environment Curve:



Test Result:

No problem was found during the temperature variation operation test.

Cold start and hot start test

Test Date: 2014-07-04

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

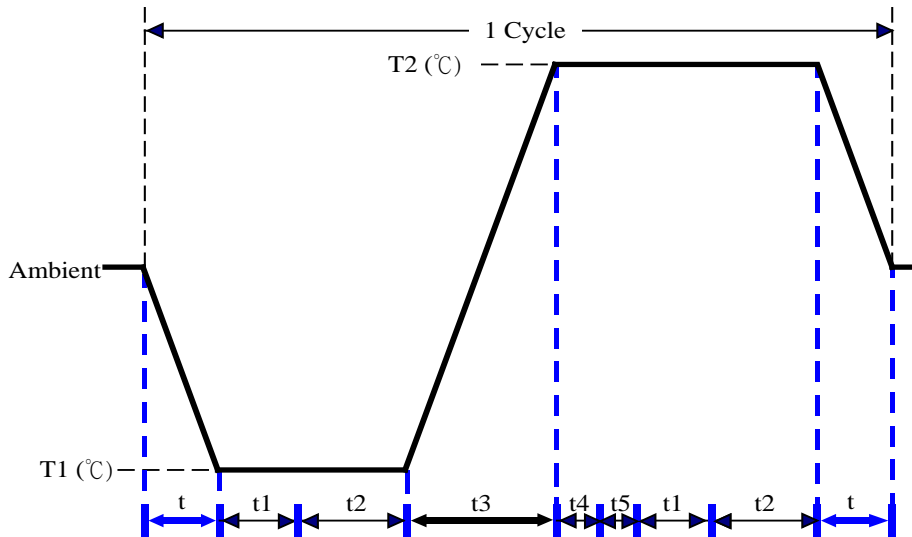
TERCHY. TECH. CORP.

Model: MHU-150LB

Date of Calibration: 2014/03/17

Serial Number: 961138

Test Condition:



Parameters	Description
T1	-5°C
T2	65°C
t1	1 hr
t2	2 hrs
t4, t5	30 mins
t, t3	2°C/min
n (Cycle)	1

t, t3: Temperature Slope

t, t1: Power Off

t2: Power On/Off test 10 times (On 2 mins / Off 5 mins)

t5: Windows soft restart test 2 times

Test software: Windows 7 Ultimate x32 Edition

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.